

NTHS4101PT1G-VB Datasheet P-Channel 30-V (D-S) MOSFET

PRODUC	CT SUMMARY		
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)
- 30	0.030 at V _{GS} = - 10 V	- 5.1	5.1 nC
- 30	0.042 at V _{GS} = - 4.5 V	- 4.1	3.1110

FEATURES

• Halogen-free According to IEC 61249-2-21 Available

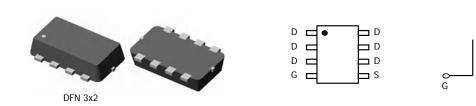
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• Trench Power MOSFET

APPLICATIONS

· Load Switch





Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	- 30	V
Gate-Source Voltage		V _{GS}	± 20	v
	T _C = 25 °C		- 5.1	
Continuous Drain Current (T ₁ = 150 °C)	T _C = 70 °C		- 4.1	
Continuous Diain Current (1) = 150°C)	T _A = 25 °C	I _D	- 4.1 ^{b, c}	
	T _A = 70 °C		- 3.3 ^{b, c}	A
Pulsed Drain Current	4	I _{DM}	- 20	
	T _C = 25 °C		- 2.5	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	- 1.67 ^{b, c}	
	T _C = 25 °C		3.0	
	T _C = 70 °C	P	2.0	W
Maximum Power Dissipation	T _A = 25 °C	P _D	2.0 ^{b, c}	VV
	T _A = 70 °C	1	1.3 ^{b, c}	
Operating Junction and Storage Temperature	e Range	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATI	NGS				
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	t ≤ 5 s	R _{thJA}	55	62.5	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R _{thJF}	34	41	0/11

Notes:

a. Based on $T_C = 25 \text{ °C}$. b. Surface Mounted on 1" x 1" FR4 board.

c. t = 5 s.

d. Maximum under Steady State conditions is 110 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = -250 \mu A$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L _ 250 uA		- 31			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.5		- mV/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = -250 \ \mu A$	- 1.0		- 3.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA	
Zana Cata Maltana Drain Current		$V_{DS} = -30 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$			- 1	μΑ	
Zero Gate Voltage Drain Current	IDSS	V_{DS} = - 30 V, V_{GS} = 0 V, T_{J} = 55 °C			- 10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \leq$ - 5 V, V_{GS} = - 10 V	- 20			А	
	Р	V _{GS} = - 10 V, I _D = - 4.1 A		0.030		_	
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 1.0 A		0.042		Ω	
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 4.1 A		8		S	
Dynamic ^b	1						
Input Capacitance	C _{iss}			450			
Output Capacitance	C _{oss}	V_{DS} = - 15 V, V_{GS} = 0 V, f = 1 MHz		80		pF	
Reverse Transfer Capacitance	C _{rss}			63			
Total Gate Charge	Qg	V_{DS} = - 15 V, V_{GS} = - 10 V, I_D = - 4.1 A		10	15	nC	
Total Gate Charge				5.1	8		
Gate-Source Charge	Q _{gs}	$V_{\rm DS}$ = - 15 V, $V_{\rm GS}$ = - 4.5 V, $I_{\rm D}$ = - 4.1 A		1.8			
Gate-Drain Charge	Q _{gd}			2.5			
Gate Resistance	R _g	f = 1 MHz		7		Ω	
Turn-On Delay Time	t _{d(on)}			40	60		
Rise Time	t _r	V_{DD} = - 15 V, R_L = 4.6 Ω		80	120		
Turn-Off Delay Time	t _{d(off)}	$\text{I}_\text{D}\cong$ - 3.3 A, V_GEN = - 4.5 V, R_g = 1 Ω		20	30		
Fall Time	t _f			12	20	D C	
Turn-On Delay Time	t _{d(on)}			5	10	– ns –	
Rise Time	t _r	V_{DD} = - 15 V, R_L = 4.6 Ω		13	20		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 3.3 A, V_{GEN} = - 10 V, R_g = 1 Ω		20	30		
Fall Time	t _f			10	15		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C			- 2.5	^	
Pulse Diode Forward Current ^a	I _{SM}				- 20	A	
Body Diode Voltage	V _{SD}	I _S = - 3.3 A		- 0.8	- 1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			20	30	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 2.2 A di/dt = 100 A/m = 25 eV		20	30	nC	
Reverse Recovery Fall Time	t _a	$I_F = -3.3 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		14			
Reverse Recovery Rise Time	t _b			6	İ	ns	

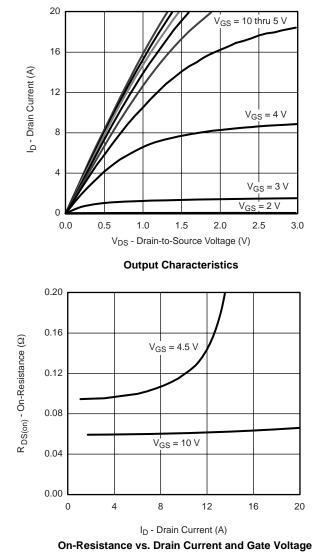
Notes:

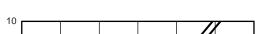
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 % b. Guaranteed by design, not subject to production testing.

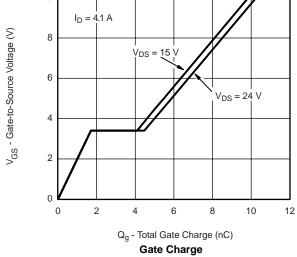
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

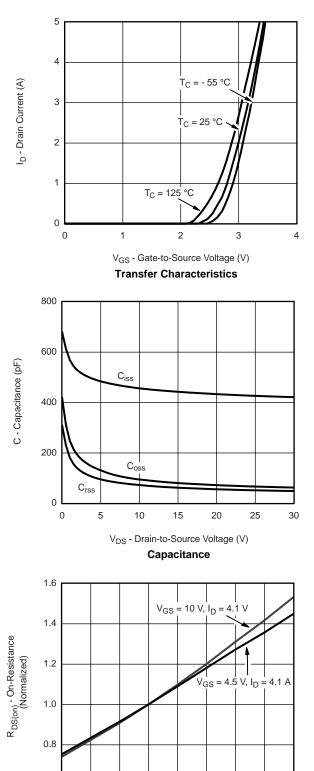


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted









0.6

- 50

- 25

0

25

50

T_J - Junction Temperature (°C)

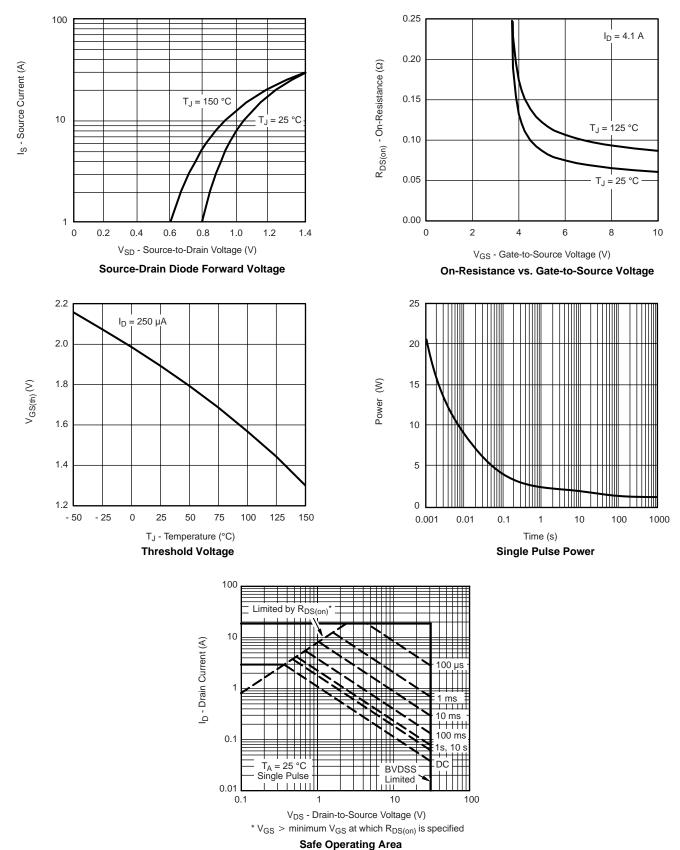
On-Resistance vs. Junction Temperature

75

100

125 150



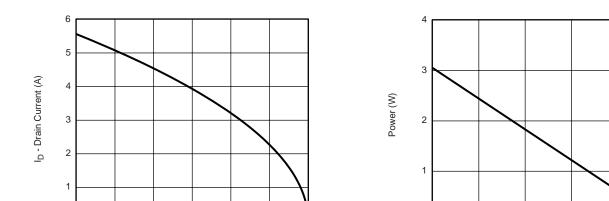


TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

T_C - Case Temperature (°C)

Current Derating*





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

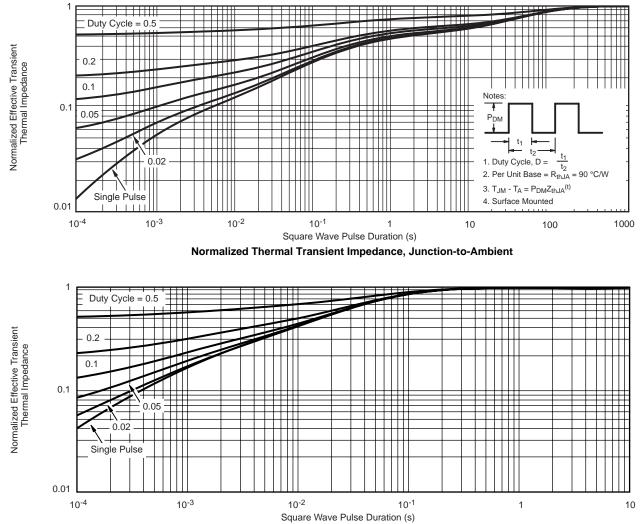
* The power dissipation P_D is based on $T_{J(max)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

T_C - Case Temperature (°C)

Power, Junction-to-Foot



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

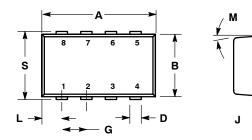


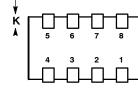
Normalized Thermal Transient Impedance, Junction-to-Foot

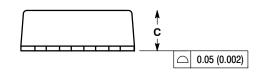


PACKAGE DIMENSIONS

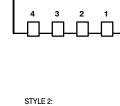
ChipFET CASE 1206A-03 ISSUE D







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TYLE 2:	
2.	GATE 1

۷.	
4.	GATE 2
5.	DRAIN 2
6.	DRAIN 2
7.	DRAIN 1
8.	DRAIN 1

1.	DIMENSIONING AND TOLERANCING PER ANSI
	V14 EM 1000

- DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
 MOLD GATE BURRS SHALL NOT EXCEED 0.13 MM PER SIDE.
 LEADFRAME TO MOLDED BODY OFFSET IN HORIZONTAL AND VERTICAL SHALL NOT EXCEED 0.08 MM.
 DIMENSIONS A AND B EXCLUSIVE OF MOLD GATE BURRS.
 NOMOLD FLASH ALLOWED ON THE TOP AND BOTTOM LEAD SURFACE.
 1206A-01 AND 1206A-02 OBSOLETE. NEW STANDARD IS 1206A-03.

	MILLIN	IETERS	INCHES	
DIM	MIN	MIN MAX		MAX
Α	2.95	3.10	0.116	0.122
В	1.55	1.70	0.061	0.067
C	1.00	1.10	0.039	0.043
D	0.25	0.35	0.010	0.014
G	0.65 BSC		0.025 BSC	
J	0.10	0.20	0.004	0.008
K	0.28	0.42	0.011	0.017
L	0.55 BSC		0.02	2 BSC
М	5 ° NOM		5 °	NOM
S	1.80	2.00	0.072	0.080



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